

<b>Notice of References Cited</b>	Application/Control No. <b>09/686,682</b>		Applicant(s)/Patent Under Reexam <b>Onoe et al.</b>	
	Examiner <b>Man Phan</b>		Art Unit <b>2665</b>	Page 1 of 1

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**NON-PATENT DOCUMENTS**

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